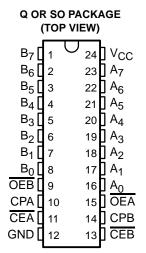
CY29FCT52T 8-BIT REGISTERED TRANSCEIVER

SCCS010A - MAY 1994 - REVISED OCTOBER 2001

- Function, Pinout, and Drive Compatible With FCT, F Logic, and AM2952
- Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- I_{off} Supports Partial-Power-Down Mode Operation
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- 64-mA Output Sink Current
 32-mA Output Source Current



description

The CY29FCT52T has two 8-bit back-to-back registers that store data flowing in both directions between two bidirectional buses. Separate clock, clock enable, and 3-state output-enable signals are provided for each register. Both A outputs and B outputs are specified to sink 64 mA.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

PIN DESCRIPTION

NAME	DESCRIPTION
Α	A register inputs or B register outputs
В	B register inputs or A register outputs
CPA	Clock for the A register. When CEA is low, data enters the A register on the low-to-high transition of the CPA signal.
CEA	Clock enable for the A register. When $\overline{\text{CEA}}$ is low, data enters the A register on the low-to-high transition of the CPA signal. When $\overline{\text{CEA}}$ is high, the A register holds its contents, regardless of CPA signal transitions.
OEA	Output enable for the A register. When OEA is low, the A register outputs are enabled onto the B lines. When OEA is high, the A outputs are in the high-impedance state.
СРВ	Clock for the B register. When CEB is low, data enters the B register on the low-to-high transition of the CPB signal.
CEB	Clock enable for the B register. When $\overline{\text{CEB}}$ is low, data enters the B register on the low-to-high transition of the CPB signal. When $\overline{\text{CEB}}$ is high, the B register holds its contents, regardless of CPA signal transitions.
OEB	Output enable for the B register. When OEB is low, the B register outputs are enabled onto the A lines. When OEB is high, the B outputs are in the high-impedance state.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PAC	CKAGET	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING		
	QSOP – Q	Tape and reel	6.3	CY29FCT52CTQCT	29FCT52C		
–40°C to 85°C	°C to 85°C SOIC – SO	Tube	6.3 CY29FCT52CTSOC		20505520		
	30IC - 30	Tape and reel 6.3 CY29FC		CY29FCT52CTSOCT	29FCT52C		

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

Function Tables

FUNCTION TABLE

	INPUTS		INTERNAL	FUNCTION
D	СР	CE	Q	FUNCTION
Х	Х	Н	NC	Hold data
L		L	L	Load data
Н		L	Н	Load data

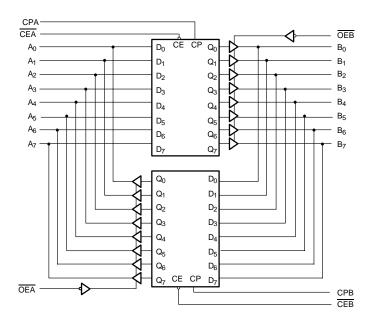
H = High logic level, L = Low logic level, X = Don't care, NC = No change

OUTPUT CONTROL

ŌĒ	INTERNAL Q	Y OUTPUTS	FUNCTION
Н	Х	Z	Disable outputs
L	L	L	Enoble sutnute
L	Н	Н	Enable outputs

H = High logic level, L = Low logic level, X = Don't care, Z = High impedance (off) state.

logic diagram





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absolute maximum rating over operating free-air temperature range (unless otherwise noted)†

Supply voltage range to ground potential		0.5 V to 7 V
DC input voltage range		0.5 V to 7 V
DC output voltage range		0.5 V to 7 V
DC output current (maximum sink current/	pin)	120 mA
Package thermal impedance, θ_{JA} (see No	te 1): Q package	61°C/W
	SO package	46°C/W
Ambient temperature range with power ap	plied, T _A	65°C to 135°C
Storage temperature range, T _{stq}		65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
V _{IL}	Low-level input voltage			0.8	٧
ЮН	High-level output current			-32	mA
loL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS					
VIK	$V_{CC} = 4.75 \text{ V},$	$I_{IN} = -18 \text{ mA}$			-0.7	-1.2	V
Vari	$I_{OH} = -32 \text{ mA}$						V
VOH	V _{CC} = 4.75 V	$I_{OH} = -15 \text{ mA}$		2.4	3.3		V
V _{OL}	$V_{CC} = 4.75 \text{ V},$	$I_{OL} = 64 \text{ mA}$			0.3	0.55	V
V _H	All inputs				0.2		V
Ι _Ι	$V_{CC} = 5.25 \text{ V},$	$V_{IN} = V_{CC}$				5	μΑ
lіН	$V_{CC} = 5.25 \text{ V},$	$V_{IN} = 2.7 \text{ V}$				±1	μΑ
I _{IL}	$V_{CC} = 5.25 \text{ V},$	$V_{IN} = 0.5 V$				±1	μΑ
los [‡]	$V_{CC} = 5.25 \text{ V},$	V _{CC} = 5.25 V, V _{OUT} = 0 V				-225	mA
l _{off}	$V_{CC} = 0 V$	V _{CC} = 0 V, V _{OUT} = 4.5 V					μΑ
Icc	$V_{CC} = 5.25 \text{ V}, V_{IN} \le 0$	$.2 \text{ V, V}_{IN} \ge \text{V}_{CC} - 0.2 \text{ V}$			0.1	0.2	mA
ΔlCC	V _{CC} = 5.25 V, V _{IN} = 3	.4 V , $f_1 = 0$, Outputs ope	n		0.5	2	mA
ICCD¶	$\frac{V_{CC}}{OEA} = 5.25 \text{ V}$, One inp	ut switching at 50% duty $V_{IN} \le 0.2 \text{ V or } V_{IN} \ge V_{CC}$	cycle, Outputs open, – 0.2 V		0.06	0.12	mA/ MHz
	V _{CC} = 5.25 V,	One bit switching at f ₁ = 5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4	
I _C #	$f_0 = 10 \text{ MHz},$	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1.2	3.4	mA
ıC	Outputs open, OEA or OEB = GND	Eight bits switching at f ₁ = 2.5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		1.6	3.2	IIIA
		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.9	12.2	
C _i					5	10	pF
Co		_			9	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

 $^{\#}$ IC = ICC + Δ ICC \times D_H \times N_T + ICCD (f₀/2 + f₁ \times N₁)

Where:

IC = Total supply current

I_{CC} = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input (V_{IN} = 3.4 V)

D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

ICCD = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

Values for these conditions are examples of the ICC formula.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

[§] Per TTL driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

This parameter is derived for use in total power-supply calculations.

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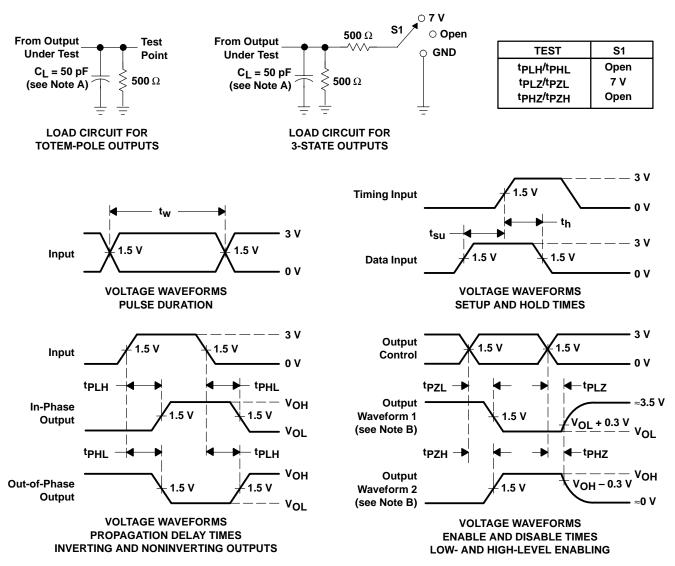
timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

	PARAMETER						
t _W	t _W Pulse duration, clock						
Γ.	Setup time, before CPA↑ or CPB↑	Data	2.5		20		
t _{su}	Setup time, before CPAT of CPBT	3		ns			
Ĺ.	Hold time, after CPA↑ or CPB↑	Data	1.5				
t _h	Hold liftle, after CPAT of CPBT	2	, and the second	ns			

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
^t PLH	CPA, CPB	A, B	2	6.3	20
^t PHL	CPA, CPB	А, Б	2	6.3	ns
^t PZH	OEA or OEB	A or B	1.5	7	no
^t PZL	OEA OF OEB	AUB	1.5	7	ns
^t PHZ	OEA or OEB	A or B	1.5	6.5	20
tPLZ	OEA OI OEB	AUID	1.5	6.5	ns

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material Peak reflow			(6)
						(4)	(5)		
CY29FCT52CTQCT	Active	Production	SSOP (DBQ) 24	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	29FCT52C
CY29FCT52CTQCT.B	Active	Production	SSOP (DBQ) 24	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	29FCT52C
CY29FCT52CTSOC	Active	Production	SOIC (DW) 24	25 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	29FCT52C
CY29FCT52CTSOC.B	Active	Production	SOIC (DW) 24	25 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	29FCT52C

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

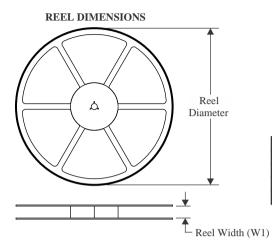
⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

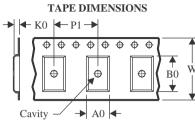
⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY29FCT52CTQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

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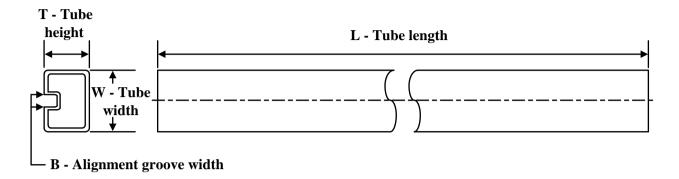
*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ı	CY29FCT52CTQCT	SSOP	DBQ	24	2500	353.0	353.0	32.0

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TUBE

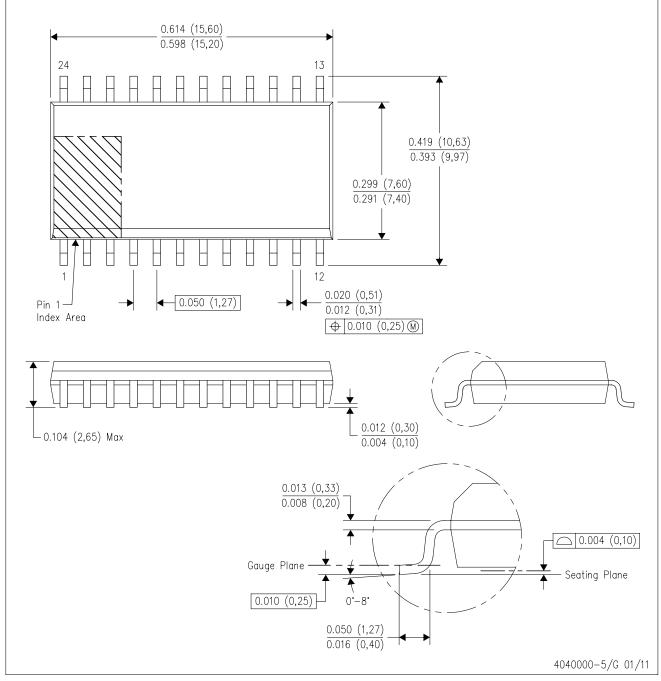


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CY29FCT52CTSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6
CY29FCT52CTSOC.B	DW	SOIC	24	25	506.98	12.7	4826	6.6

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



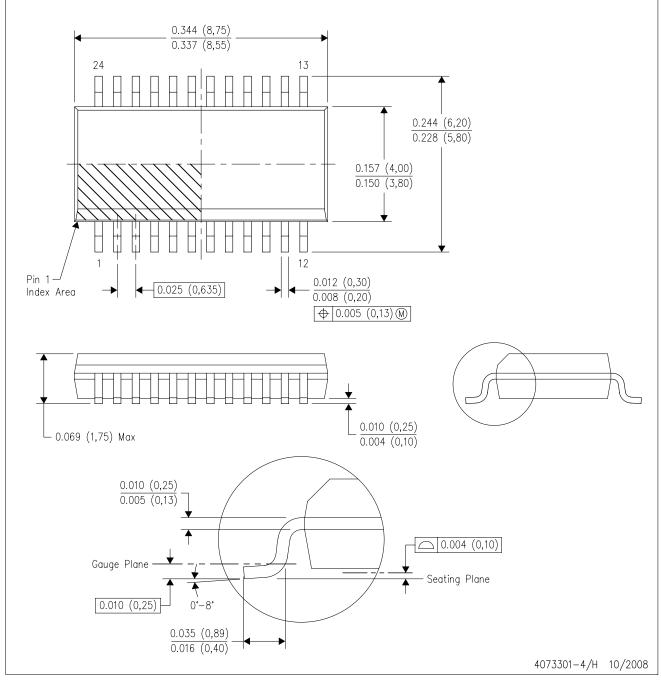
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



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